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 Neural Networks, IEEE Transactions on , Volume: 6 , Issue: 6 , Nov. 1995
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 Computers, IEEE Transactions on , Volume: 39 , Issue: 10 , Oct. 1990
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3 Linearizing the directory growth in order preserving extendible hashing
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 Data Engineering, 1988. Proceedings. Fourth International Conference on , 1-5 Feb. 1988
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Wann, C.H.; Noda, K.; Tanaka, T.; Yoshida, M.; Chenming Hu;
Electron Devices, IEEE Transactions on , Volume: 43 , Issue: 10 , Oct. 1996
Pages:1742 - 1753

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2 Transconductance enhancement due to back bias for submicron NMOSFET

Jyh-Chyurn Guo; Ming-Chien Chang; Chih-Yuan Lu; Hsu, C.C.-H.; Chung, S.S.-S.;
Electron Devices, IEEE Transactions on , Volume: 42 , Issue: 2 , Feb. 1995
Pages:288 - 294

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3 Performance and reliability evaluation of high dielectric LDD spacer on deep sub-micrometer LDD MOSFET

Jyh-Chyurn Guo; Chih-Yua Lu; Hsu, C.C.-H.; Pole-Shan Lin; Chung, S.S.-S.;
Electron Devices, IEEE Transactions on , Volume: 41 , Issue: 7 , July 1994
Pages:1239 - 1248

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4 Two-dimensional analysis of short-channel delta-doped GaAs MESFETs

Tian, H.; Kim, K.W.; Littlejohn, M.A.; Bedair, S.M.; Witkowski, L.C.;
Electron Devices, IEEE Transactions on , Volume: 39 , Issue: 9 , Sept. 1992
Pages:1998 - 2006

[\[Abstract\]](#) [\[PDF Full-Text \(768 KB\)\]](#) **IEEE JNL**

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5 Boron diffusion model refinement and its effect on the calculation of reverse short channel effect

Hane, M.; Rafferty, C.S.; Ikezawa, T.; Matsumoto, H.;
Simulation of Semiconductor Processes and Devices, 1996. SISPAD 96. 1996
International Conference on , 2-4 Sept. 1996
Pages:15 - 16

[Abstract] [PDF Full-Text (148 KB)] IEEE CNF

6 25 nm CMOS design considerations

Taur, Y.; Wann, C.H.; Frank, D.J.;
Electron Devices Meeting, 1998. IEDM '98 Technical Digest., International , 6-9
Dec. 1998
Pages:789 - 792

[Abstract] [PDF Full-Text (340 KB)] IEEE CNF

7 HC reliability of 0.5 µm BiCMOS transistors: dependence on link base slot depth and the design implications for reliability and performance

Varker, C.J.; Kirchgessner, J.; Zirkle, T.; Howard, E.;
Reliability Physics Symposium, 1994. 32nd Annual Proceedings., IEEE
International , 11-14 April 1994
Pages:17 - 22

[Abstract] [PDF Full-Text (576 KB)] IEEE CNF

8 Half micron BiCMOS device and process modeling

Borucki, L.; Zirkle, T.; Kirchgessner, J.; Drennan, P.;
Bipolar/BiCOMS Circuits and Technology Meeting, 1993., Proceedings of the
1993 , 4-5 Oct. 1993
Pages:97 - 103

[Abstract] [PDF Full-Text (732 KB)] IEEE CNF
